

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10588023	HECKER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Hanh Phan	2613

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
398	183, 184, 185, 186, 188, 192, 195, 196, 197, 198, 79, 65, 152	02/12/2009	HP
385	11, 3, 39	02/12/2009	HP
359	246, 254, 245	02/12/2009	HP

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST SEARCH SEE ATTACHED PRINTOUT IN THE FILE	02/12/2009	HP
IEEE SEARCH	02/12/2009	HP
JPO SEARCH	02/12/2009	HP

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>